

WHAT IS CLAIMED IS:

1 1. An apparatus comprising:

2 a charge pump having a capacity that is preset to a  
3 particular value; and

4 a measuring circuit to measure an actual capacity of the  
5 charge pump and to reset the capacity of the charge pump to a  
6 value based on the measured capacity.

1 2. The apparatus of claim 1 wherein an output of the charge  
2 pump is preset to operate at particular voltage and current  
3 levels.

1 3. The apparatus of claim 1 wherein the measuring circuit  
2 includes a temperature sensor.

1 4. The apparatus of claim 1 wherein the measuring circuit  
2 includes a voltage sensor to sense a voltage at an input of  
3 the charge pump.

1 5. The apparatus of claim 1 wherein the measuring circuit  
2 includes a voltage sensor to sense a voltage at an output of  
3 the charge pump.

1 6. The apparatus of claim 1 wherein the measuring circuit  
2 includes a current sensor to sense a current at an output of  
3 the charge pump.

1 7. An apparatus comprising:

2 an array of memory cells; and

3 a charge pump circuit coupled to the array of memory  
4 cells to drive the array of memory cells, the charge pump  
5 circuit comprising:

6 a charge pump having a capacity that is preset to a  
7 particular value, and

8 a measuring circuit to measure an actual capacity of  
9 the charge pump and to reset the capacity of the charge  
10 pump to a value based on the measured capacity.

1 8. The apparatus of claim 7 wherein an output of the charge  
2 pump is preset to operate at particular voltage and current  
3 levels.

1 9. The apparatus of claim 7 wherein the measuring circuit  
2 includes a temperature sensor.

1 10. The apparatus of claim 7 wherein the measuring circuit  
2 includes a voltage sensor to sense a voltage at an input of  
3 the charge pump.

1 11. The apparatus of claim 7 wherein the measuring circuit  
2 includes a voltage sensor to sense the voltage at an output of  
3 the charge pump.

1 12. The apparatus of claim 7 wherein the measuring circuit  
2 includes a current sensor to sense a current at an output of  
3 the charge pump.

1 13. A computer system comprising:

2 a central processor; and

3 a memory coupled to the central processor, the memory  
4 comprising:

5 an array of memory cells, and

6 a charge pump circuit coupled to the array of memory  
7 cells to drive the array of memory cells, the charge pump  
8 circuit comprising:

9 a charge pump having a capacity that is preset to a  
10 particular value, and

11 a measuring circuit to measure an actual capacity of  
12 the charge pump and to reset the capacity of the charge  
13 pump to a value based on the measured capacity.

1 14. The computer system of claim 13 wherein an output of the  
2 charge pump is preset to operate at particular voltage and  
3 current levels.

1 15. The computer system of claim 13 wherein the measuring  
2 circuit includes a temperature sensor.

1 16. The computer system of claim 13 wherein the measuring  
2 circuit includes a voltage sensor to sense a voltage at an  
3 input of the charge pump.

1 17. The computer system of claim 13 wherein the measuring  
2 circuit includes a voltage sensor to sense a voltage at an  
3 output of the charge pump.

1 18. The computer system of claim 13 wherein the measuring  
2 circuit includes a current sensor to sense the current at an  
3 input of the charge pump.

1 19. A method comprising:

2 measuring a capacity of a charge pump; and  
3 resetting the capacity of the charge pump to a value  
4 based on the measured capacity.

1 20. The method of claim 19 further comprising presetting a  
2 capacity of the charge pump to a particular value.

3 21. The method of claim 20 wherein presetting a capacity of  
4 the charge pump to a particular value includes presetting the  
5 charge pump to particular voltage and current levels.

1 22. The method of claim 19 wherein measuring the capacity of  
2 the charge pump includes measuring a temperature of the charge  
3 pump.

1 23. The method of claim 19 wherein measuring the capacity of  
2 the charge pump includes measuring a voltage at an input of  
3 the charge pump.

1 24. The method of claim 19 wherein measuring the capacity of  
2 the charge pump includes measuring a voltage at an output of  
3 the charge pump.

1 25. The method of claim 19 wherein measuring the capacity of  
2 the charge pump includes measuring a current at an output of  
3 the charge pump.